

Size effects on stability and polarization dynamics in ferroelectrics

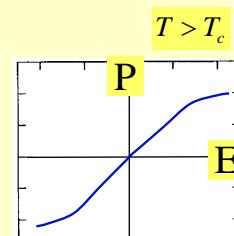
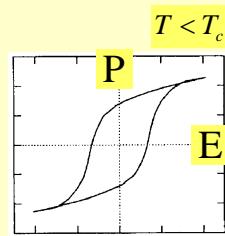
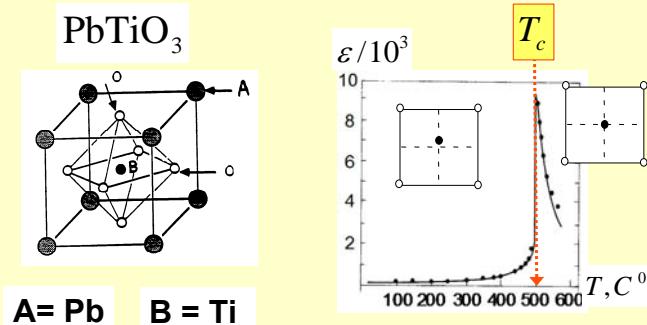
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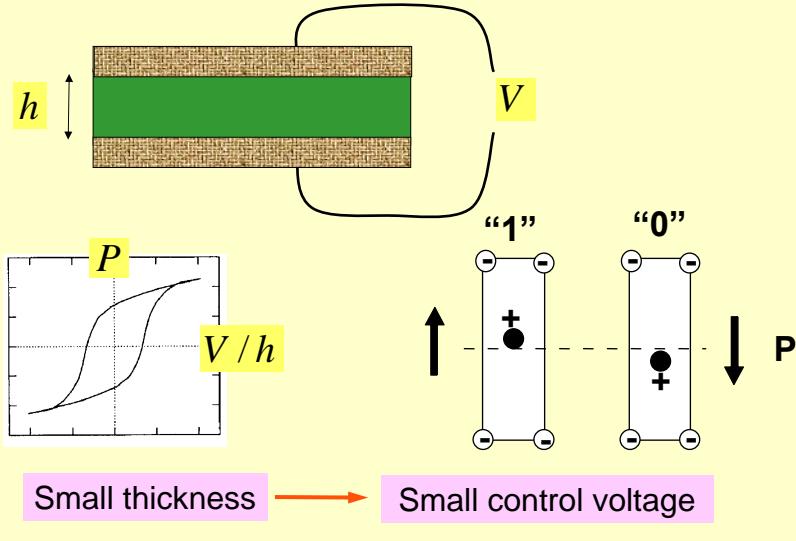
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Ferroelectrics



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Storage of information in a ferroelectric



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Size effect in ferroelectric thin films

Materials:

$\text{Pb}(\text{Zr},\text{Ti})\text{O}_3$ (PZT)
 $\text{SrBi}_2\text{Ta}_2\text{O}_9$

Thickness < 100 nm

The problem for down-scaling
→ ferroelectric/electrode coupling

Surface interaction

Incomplete screening

Surface induced asymmetry

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Ferroelectric/electrode coupling

Surface interaction

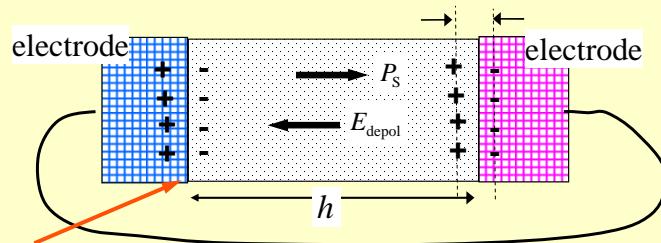
Incomplete screening

Surface-induced asymmetry

Interface locally suppresses ferroelectricity

Bound and free charges are separated at interface

Interface “likes” one direction of polarization



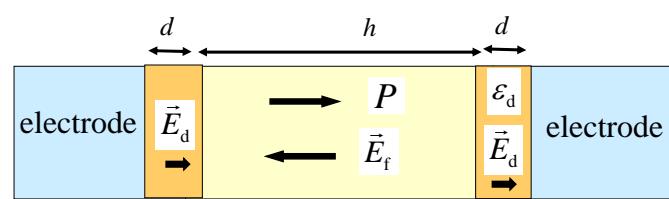
Can be modeled as a passive layer

$$E_{\text{depol}} \propto \frac{P_s}{h}$$

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Energy of ferroelectric capacitor

$$\Phi_{\text{bulk}} = h \left(\frac{\alpha}{2} P^2 + \frac{\beta}{4} P^4 \right) + \Phi_{\text{surf}} + \Phi_{\text{el}}$$



$$\Phi_{\text{surf-I}} = \frac{\eta}{2} P^2 + \zeta \vec{P}$$

$$\Phi_{\text{surf-II}} = \frac{\eta}{2} P^2 - \zeta \vec{P}$$

$$D_f = P + \epsilon_b E_f \quad D_d = \epsilon_d E_d$$

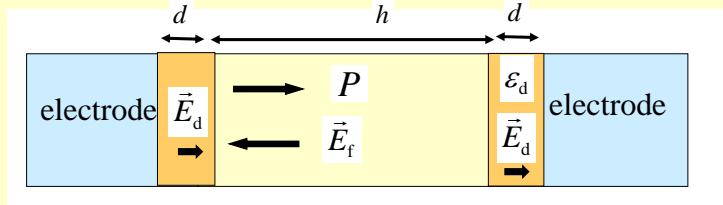
ϵ_b -background permittivity

$$\Phi_{\text{el}} = h \frac{\epsilon_b E_f^2}{2} + 2d \frac{\epsilon_d E_d^2}{2}$$

$$\epsilon_b \approx 10 \quad \epsilon_b \ll \epsilon_f$$

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Electrostatic energy of short-circuited capacitor



$$\Phi_{\text{el}} = h \frac{\epsilon_b E_f^2}{2} + 2d \frac{\epsilon_d E_d^2}{2} \quad D_f = P + \epsilon_b E_f \quad D_d = \epsilon_d E_d$$

Electrostatics

$$P + \epsilon_b E_f = \epsilon_d E_d$$

$$hE_f + 2dE_d = 0$$

$$E_d = \frac{hP}{h\epsilon_d + 2d\epsilon_b}$$

$$E_f = -\frac{2dP}{h\epsilon_d + 2d\epsilon_b}$$

$$\Phi_{\text{el}} = \frac{dhP^2}{h\epsilon_d + 2d\epsilon_b}$$

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Total energy of short-circuited real capacitor

$$h\epsilon_d \gg 2d\epsilon_b$$

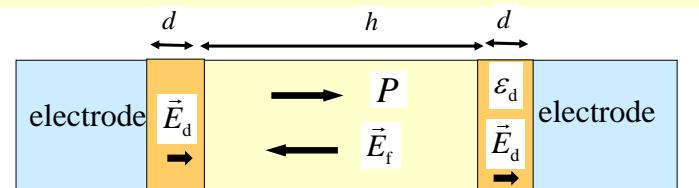
$$\lambda \equiv d / (\epsilon_d / \epsilon_0)$$

$$E_f \approx -\frac{2\lambda}{h\epsilon_0} P$$

$$\Phi_{\text{el}} \approx \frac{\lambda P^2}{\epsilon_0}$$

manly electrostatic energy in the dead layers

$$\Phi = \Phi_{\text{bulk}} + \Phi_{\text{surf}} + \Phi_{\text{el}}$$



$$\Phi_{\text{surf-I}} = \frac{\eta}{2} P^2$$

$$\Phi_{\text{el}} = \frac{\lambda P^2}{\epsilon_0}$$

$$\Phi_{\text{surf-II}} = \frac{\eta}{2} P^2$$

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Suppression of homogeneous polarization state

$$\Phi = h \left(\frac{\alpha}{2} P^2 + \frac{\beta}{4} P^4 \right) + \frac{\lambda P^2}{\varepsilon_0} + \eta P^2 = h \left(\frac{\alpha^*}{2} P^2 + \frac{\beta}{4} P^4 \right)$$

$$\alpha = \frac{T - T_0}{C \varepsilon_0}$$

$$\alpha^* = \alpha + 2 \frac{\lambda / \varepsilon_0 + \eta}{h}$$

Curie-Weiss constant

electrostatic

surface,
short-range

$$\Delta T_c(h) = -2C \frac{\lambda + \eta \varepsilon_0}{h}$$

$$h_{\text{crit}}(T) = 2(\lambda + \eta \varepsilon_0) \frac{C}{T_c - T}$$

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Suppression of homogeneous polarization state; test feature

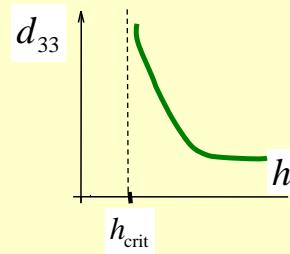
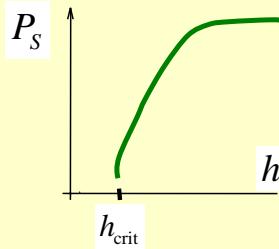
$$\Phi = h \left(\frac{\alpha^*}{2} P^2 + \frac{\beta}{4} P^4 \right)$$

$$\alpha^* = -2(\lambda + \eta \varepsilon_0) \left(\frac{1}{h_{\text{crit}}} - \frac{1}{h} \right) \quad h_{\text{crit}}(T) = 2(\lambda + \eta \varepsilon_0) \frac{C}{T_c - T}$$

$$P_s^2 = -\alpha^* / \beta$$

$$\varepsilon = -1 / 2\alpha^*$$

$$d_{33} = 2QP_s \varepsilon \propto 1/\sqrt{\alpha^*}$$



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Multi-scale approach to the size effect

Phenomenology applicable to any h

$$\Phi = h \left(\frac{\alpha}{2} P^2 + \frac{\beta}{4} P^4 \right) + \frac{\lambda P^2}{\varepsilon_0} + \eta P^2$$

$$\beta P^2 = -\alpha + 2 \frac{\lambda / \varepsilon_0 + \eta}{h}$$

$$E_f = -\frac{2\lambda}{h\varepsilon_0} P$$

Ab initio calculations (can be done for small h)

To calculate

$$\beta \quad P(h) \quad E_f(h)$$

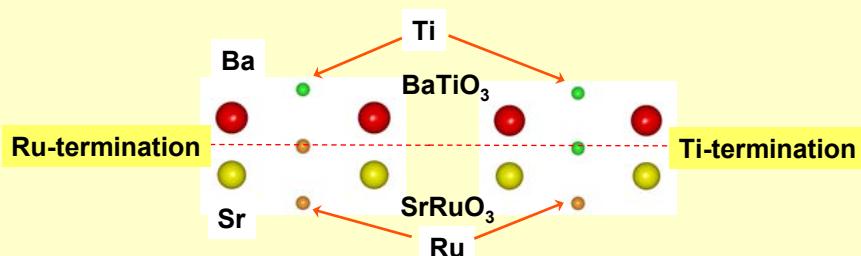
$$\frac{\partial P^2}{\partial(1/h)} \Rightarrow \lambda / \varepsilon_0 + \eta$$

$$\frac{\partial}{\partial h} \left(\frac{P}{E_f} \right) \Rightarrow 1/\lambda$$

(Tagantsev *et al.*, 2008)

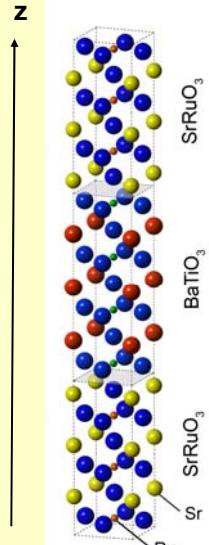
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System under consideration



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Calculations



SrRuO₃/BaTiO₃/SrRuO₃ stack

Frozen phonons
“hard” electrode”

$$\Delta E(\xi)$$

Energy as a function
of the amplitude of
the soft-mode
displacements

$u_m = 2.2\%$ -in-plane compression
to stabilize tetragonal phase

Full relaxation
“normal” electrode

$$\Delta E(x_z^{(1)}, x_z^{(2)}, x_z^{(3)} \dots)$$

$$\min[\Delta E]$$

all atoms



$$(x_z^{(1)}, x_z^{(2)}, x_z^{(3)} \dots)$$

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Technical

SrRuO₃/BaTiO₃/SrRuO₃ stack

Frozen phonons

$$\Delta E(\xi)$$

Full relaxation

$$(x_z^{(1)}, x_z^{(2)}, x_z^{(3)} \dots)$$

VASP

DFT with GGA

Monkhorst-Pack grid = 6x6x1

$E_{\text{cut-off}} = 400$ eV

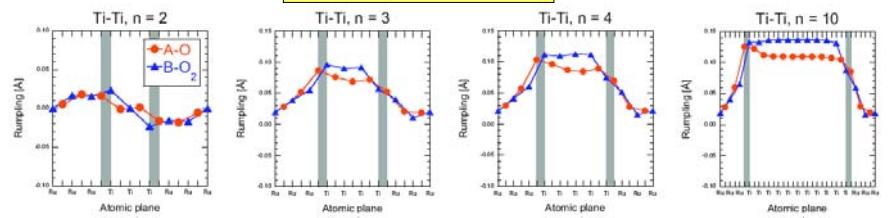
$F_{\text{H-F}} < 1$ meV/A;

Short-circuited stack = periodic boundary conditions

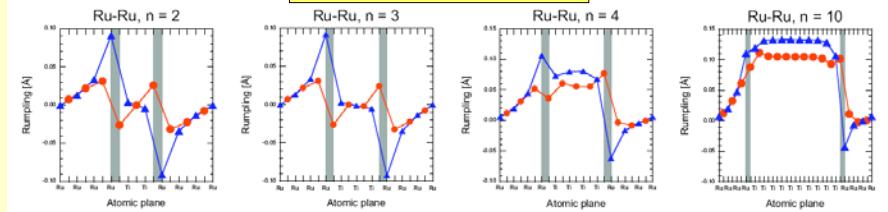
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Full relaxation - rumplings

Ti-Ti termination



Ru-Ru termination

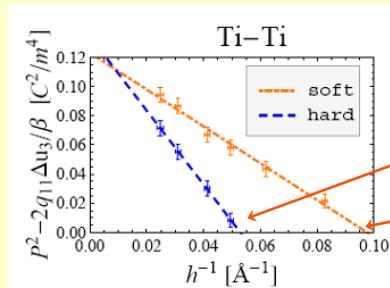


(Tagantsev *et al.*, 2008)

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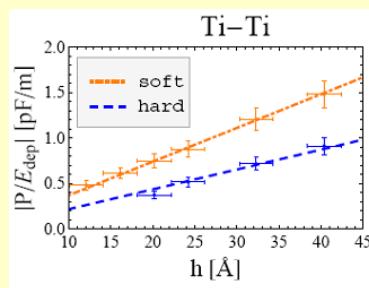
Determination of λ and η

$$\frac{\partial P^2}{\partial(1/h)} \Rightarrow \lambda / \epsilon_0 + \eta$$



Critical thickness

$$\frac{\partial}{\partial h} \left(\frac{P}{E_d} \right) \Rightarrow \frac{1}{\lambda}$$



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Parameters of SRO/BTO interface

Shift of T_c

$$\Delta T_c(h) = -2C \frac{\lambda + \eta \varepsilon_0}{h}$$

Parameter	Soft electrode (real)		Hard electrode	
electrostatic	Ti-Ti	Ru-Ru	Ti-Ti	Ru-Ru
λ	$0.12 \pm 0.01 \text{ \AA}$	$0.13 \pm 0.01 \text{ \AA}$	$0.20 \pm 0.01 \text{ \AA}$	$0.10 \pm 0.01 \text{ \AA}$
$\varepsilon_0 \eta$	$\pm 0.01 \text{ \AA}$	$0.01 \pm 0.01 \text{ \AA}$	$0.02 \pm 0.01 \text{ \AA}$	$0.08 \pm 0.01 \text{ \AA}$
= short-range				

- $\varepsilon_0 \eta$ is much smaller than the expected “atomic estimate” $\sim 2 \text{ \AA}$
- For realistic interfaces, the short-range contribution is relatively small

$$C \approx 1.5 \times 10^5 \text{ K}$$

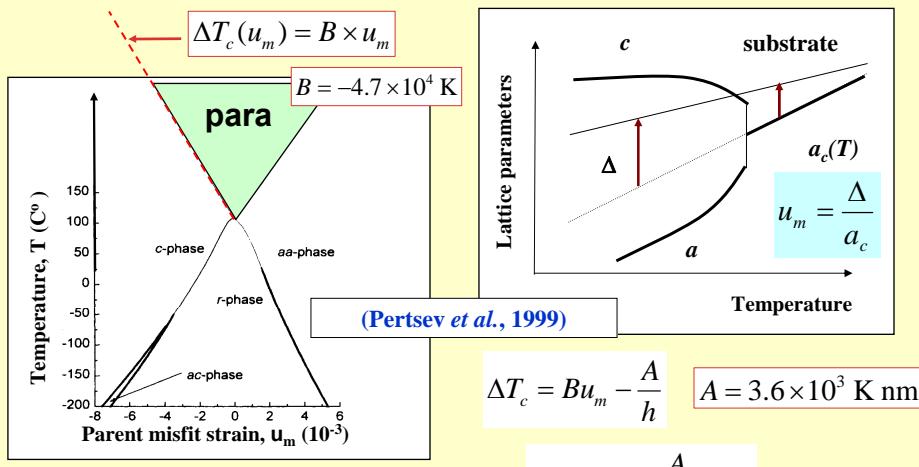
$$\lambda + \eta \varepsilon_0 \approx 1.2 \times 10^{-2} \text{ nm}$$

$$\Delta T_c(h) = -\frac{A}{h}$$

$$A \approx 2C\lambda = 3.6 \times 10^3 \text{ K nm}$$

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Size effect in STO/SRO/BTO/SRO system



BaTiO_3 on SrTiO_3 substrate

$$h_{\text{crit}} = \frac{A}{T_c - T + Bu_m}$$

$$u_m|_{RT} \approx -0.022 \rightarrow \Delta T_c(u_m) \approx 1000 \text{ K}$$

$$h_{\text{crit}}(300 \text{ K}) \approx 3.2 \text{ nm}$$

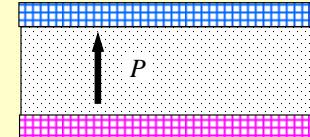
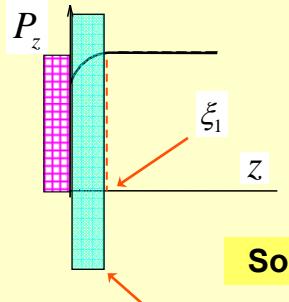
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Where is the gradient term?

$$\Phi_{\text{bulk}} / h = \frac{\alpha}{2} P^2 + \frac{\beta}{4} P^4 + \frac{\kappa}{2} \left(\frac{\partial P}{\partial z} \right)^2$$

(Kretchmer & Binder, 1979)

Out-of-plane geometry



BaTiO₃

$\xi_1 \approx 0.03 - 0.2 \text{ nm}$

ξ_1 is too small

Solution to the problem

Taken into account by

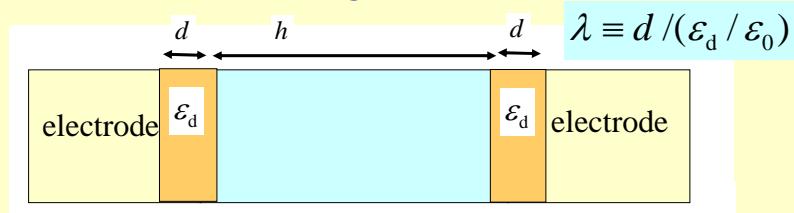
$$P = \text{const}$$

$$\Phi_{\text{surf}} = \frac{\eta}{2} P^2$$

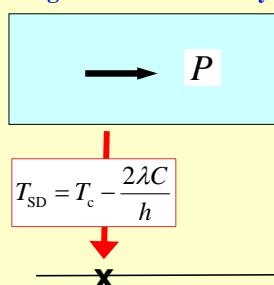
(Tagantsev et al., 2008)

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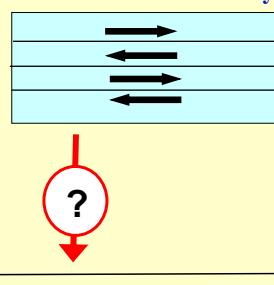
Domain instability and size effect



Single-domain instability



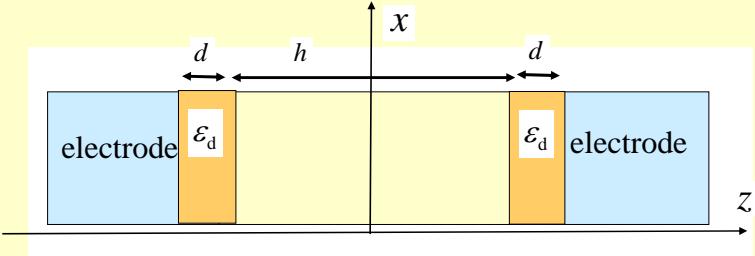
Multi-domain instability



$$T_c \quad T$$

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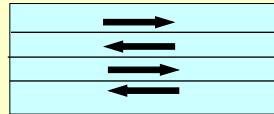
Chensky-Tarasenko instability



First-harmonics approximation
to domain pattern
(“soft” domain pattern)

Multi-domain instability

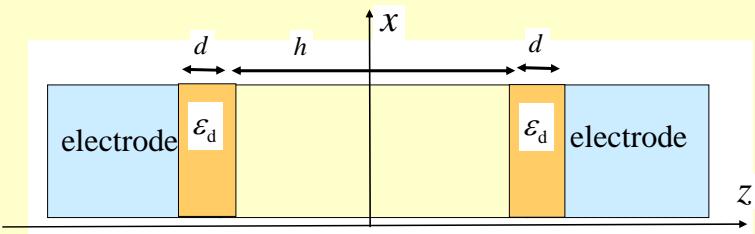
$$P_z = a \cos kx \cos qz$$



(Chensky&Tarasenko, 1982)

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Chensky-Tarasenko instability- mathematical problem



$$\Phi = \int_{-h/2}^{h/2} \left[\frac{\alpha}{2} P^2 + \frac{\beta}{4} P^4 + \frac{D}{2} \left(\frac{\partial P}{\partial x} \right)^2 + \frac{\epsilon_b}{2} E_z^2 + \frac{\epsilon_{xx}}{2} E_x^2 \right] dz dx + \epsilon_d \int_{h/2}^{h/2+d} E^2 dz dx$$

Ferroelectric

$$D_z = P_z + \epsilon_b E_z$$

$$D_x = \epsilon_{xx} E_x$$

Dead layer

$$\vec{D} = \epsilon_d \vec{E}$$

$$P_z = a \cos kx \cos qz$$

$$\operatorname{div} \vec{D} = 0 \quad \operatorname{curl} \vec{E} = 0$$

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Chensky-Tarasenko instability-result

Critical normalized thickness of the passive layer

$$\lambda_m^2 = \frac{3D\epsilon_0^2}{\epsilon_{xx}} \quad \lambda \equiv d / (\epsilon_d / \epsilon_0)$$

Single-domain instability

$$T_s = T_c - \frac{2\lambda C}{h}$$

Nothing new !

$$\lambda < \lambda_m$$

$$T_c \quad T$$

Domain period

$$\frac{W}{2} = \sqrt{h_{ct} h} \quad h_{ct} = \pi \sqrt{\epsilon_{xx} D}$$

Multi-domain instability

$$T_M = T_c - \frac{2\lambda_m C}{h}$$

$$\lambda > \lambda_m$$

$$T_c \quad T$$

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Chensky-Tarasenko instability-result for STO/SRO/BST/SRO

$$\lambda_m^2 = \frac{3D\epsilon_0^2}{\epsilon_{xx}}$$

BaTiO₃on SrTiO₃ @ RT

$$\frac{\epsilon_{xx}}{\epsilon_0} \approx 200$$

$$\sqrt{D\epsilon_0} \cong 0.17 \text{ \AA}^0$$

$$\lambda_m \cong 0.02 \text{ \AA}^0$$

BaTiO₃/SrRuO₃ interface

$$\lambda \cong 0.12 \text{ \AA}^0$$

$$\lambda > \lambda_m$$



domain instability happens first

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Chensky-Tarasenko instability-result for STO/SRO/BST/SRO@RT

SrRuO₃/BaTiO₃/SrRuO₃/SrTiO₃ @ RT

$$\lambda \cong 0.12 \text{ \AA}^0 \quad \lambda_m \cong 0.02 \text{ \AA}^0 \quad \lambda > \lambda_m \quad \text{domain instability}$$

Critical thickness

$$\Delta T_c = Bu_m - \frac{A_{\text{dom}}}{h} \quad A_{\text{dom}} = 2C\lambda_m = 0.6 \times 10^3 \text{ K nm} \quad h_{\text{crit}}(300 \text{ K}) \cong 0.5 \text{ nm}$$

Domain period

$$\frac{W}{2} = \sqrt{h_{\text{CT}}h} \quad h_{\text{CT}} = \pi \sqrt{\varepsilon_{xx} D} \approx 0.75 \text{ nm} \quad h = 30 \text{ nm} \quad \frac{W}{2} \approx 5 \text{ nm}$$

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Chensky-Tarasenko theory-domain states in field (soft-domain approximation)

Competing states

$$P_z = p$$

$$P_z = a \cos kx \cos qz$$

$$\lambda > \lambda_m$$

Single-domain instability

$$T_s = T_c - \frac{2\lambda C}{h}$$

Multi-domain instability

$$T_m = T_c - \frac{2\lambda_m C}{h}$$

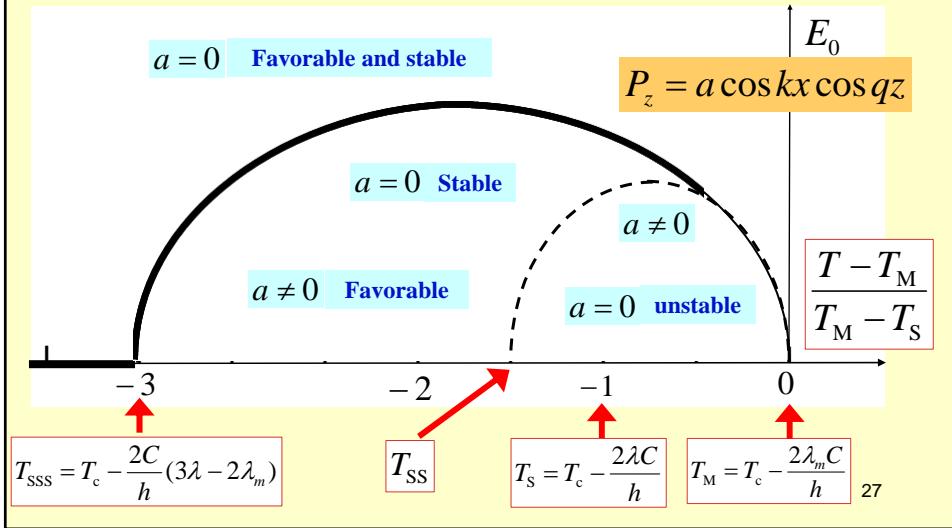
$$T_c \quad T$$

$$\Phi / \text{volume} = \frac{\alpha'(T - T_s)}{2} p^2 + \frac{\beta}{4} p^4 + \frac{\alpha'(T - T_m)}{8} a^2 + \frac{9\beta}{256} a^4 + \frac{3\beta}{8} a^2 p^2 - pE_0$$

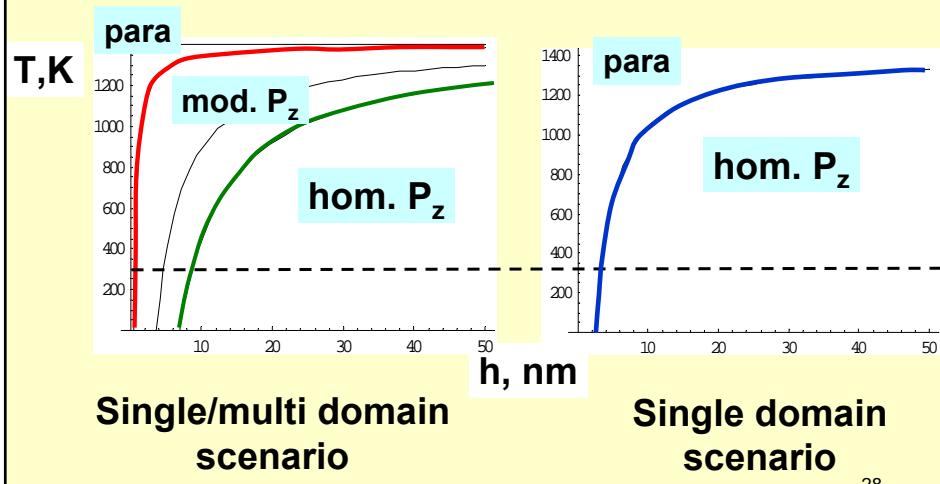
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Chensky-Tarasenko theory-map of domain state in field (soft-domain approximation)

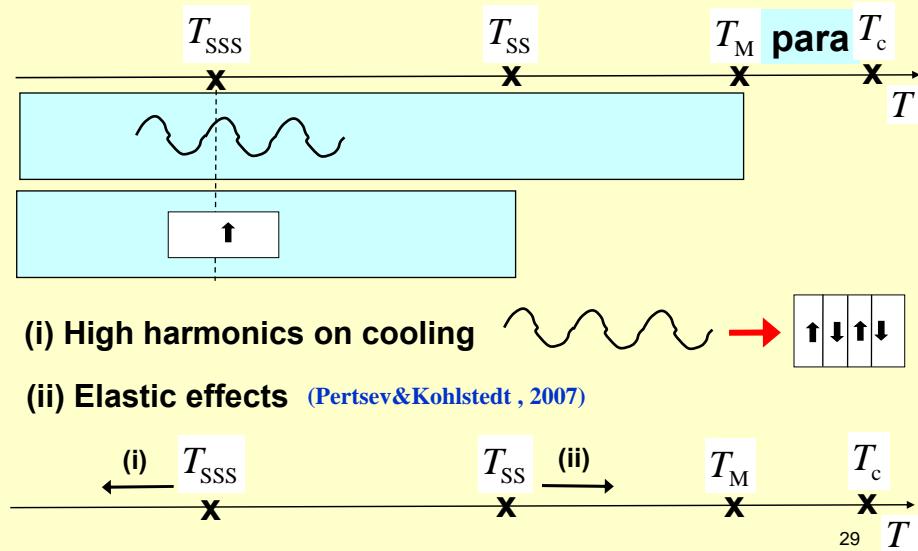
$$\lambda > \lambda_m$$



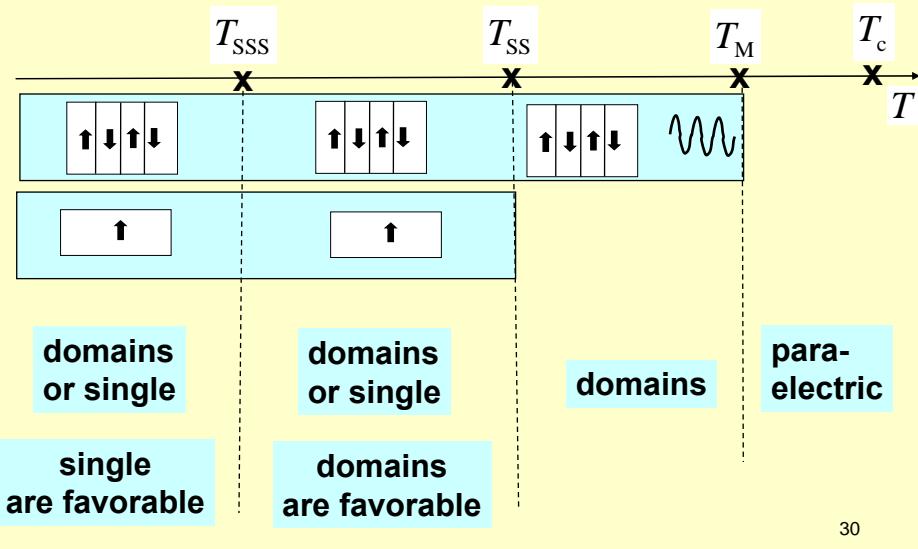
Domain state map in field in soft-domain approximation for STO/SRO/BST/SRO $E_0=0$



Soft-domain approximation and real life

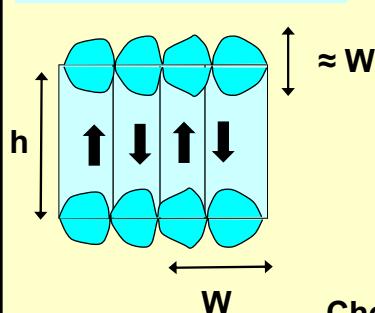


Domain state of ferroelectric capacitor



Chensky-Tarasenko theory vs. classical Mitsui-Furuichi theory (1953)

Mitsui theory ($\lambda \gg h$)



$$\Phi_{\text{el}} \propto W$$

$$\Phi_{\text{wall}} \propto \frac{h}{W}$$

$$\min[\Phi_{\text{wall}} + \Phi_{\text{el}}] \rightarrow W \propto \sqrt{h}$$

$$\frac{W}{2} = \sqrt{h_M h}$$

$$h_M = 1.7 \sqrt{\epsilon_{xx} D}$$

Chensky-Tarasenko theory ($\lambda \ll h$)

$$\frac{W}{2} = \sqrt{h_{CT} h}$$

$$h_{CT} = \pi \sqrt{\epsilon_{xx} D}$$

!!!!The available theories do not cover all situations!!!!

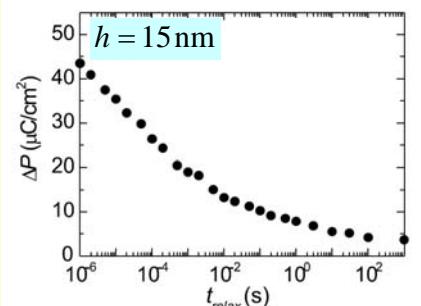
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Experiment: STO/SRO/BST/SRO

(Kim *et al.*, 2005)

$h = 5 - 30 \text{ nm}; \text{ RT}$

**Single domain state
is metastable**



First-harmonics-approximation theory for $h = 15 \text{ nm}$

$$T_{\text{SSS}} = 750$$

X

$$T_{\text{SS}} = 1100$$

X

$$T_M = 1350$$

X

$$T_c = 1400$$

X

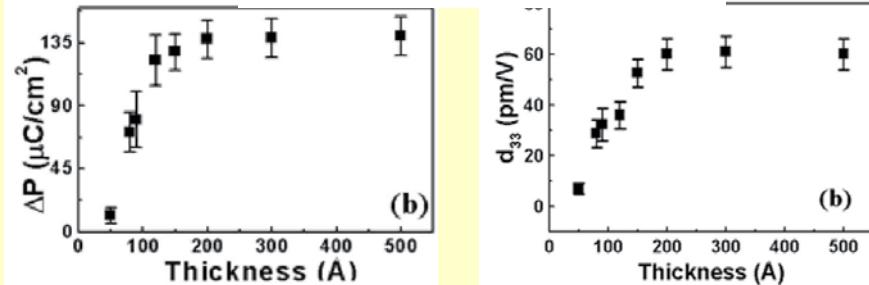
T, K

Meta-stability of S-D state

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Experiment: STO/SRO/PZT/SRO

“Domain assisted” size effects

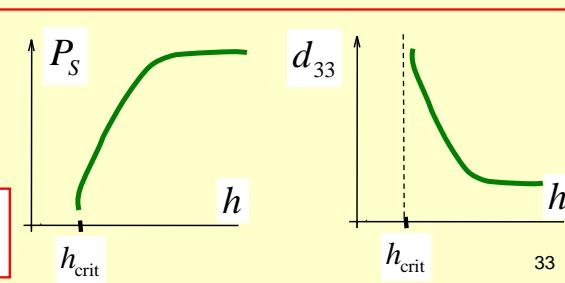


(Nagarajan *et al.*, 2006)

$\text{PbZr}_{0.2}\text{Ti}_{0.7}\text{O}_3$

$h = 5 - 50 \text{ nm}; \text{ RT}$

“homogeneous” size effects



Conclusions

The size effect in ferroelectric films is controlled by misfit strain (u_m), screening conditions (λ), parameters of ferroelectric (λ_m), and temperature (T)

$$T_{\text{SSS}} = T_c - \frac{2C}{h}(3\lambda - 2\lambda_m)$$

X

$$T_M = T_c - \frac{2\lambda_m C}{h}$$

T

$$T_S = T_c - \frac{2C}{h}(1.5\lambda - 0.5\lambda_m)$$

$$T_c(u_m)$$

With the thickness reduction, the single domain state starts competing, first of all, with a multi-domain state

Literature

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